

# Atom-Probe Field Ion Microscopy and Its Applications (Advances in Electronics & Electron Physics Supplement)



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microscopy, atom probe **An Atom-Probe Tomography Primer - Cambridge University Press** Atom-probe field ion microscopy and its applications. Front Cover its applications. Volume 20 of Advances in electronics and electron physics: Supplement. **FIELD EMISSION MICROSCOPY OF CLEAN SURFACES WITH** Electronics and Electron Physics: Advances in Electronics and Electron Physics - Supplement 20 : Atom-Probe Field Ion Microscopy and Its Applications (1989 **Sakurai Toshio - AbeBooks** 10 (Supplement), p. 121-125 5 p. Scanning electron microscopy studies of YBa<sub>2</sub>Cu<sub>3</sub>O<sub>7- $\delta$</sub>  superconductors 2nd Conference on Advances in Materials Science and Technology Abstract Book. Guo, Z., Han . Sha, W. 1993 In : Physics. 22, p. . Atom probe field ion microscopy and its application in materials research. **Code Date Author Title M 1934 Bruche, E, O. Scherzer** The Electron Microscope: An Introduction to its Fundamental. Principles and Applications . Physics of Atomic Collisions. S . Electronic and Ionic Impact Phenomena, Vol 1 Collisions of. Electrons . Advanced Techniques in Biological Electron Microscopy. H .. Atom-Probe Field Ion Microscopy and Its Applications (AEEP. **Atom-probe field ion microscopy and its applications - Google Books** Results 1 - 17 of 17 Physics Series, Microscopes & Microscopy - General & Miscellaneous, Applied Science, Books Barnes & Noble **Advances in Electronics and Electron Physics: Advances in - eBay** nology has come a long way from its early days of atom probe field ion microscopes (FIMs). It has pro- gressed through, one-dimensional (1-D) **Advances in Electronics and Electron Physics: Advances in - eBay** Atom-Probe Field Ion Microscopy and Its Applications (Advances in Electronics & Electron Physics Supplement). Sakurai, Toshio. 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Department of Electronic Engineering, University of Surrey, **Atom-Probe Field Ion Microscopy and Its Applications (Advances in** Personnel Data System Advanced Planning Data Sheet APDU: Application Polar Experiment Alfvén Propulsion Engine Alpha-Proton-Electron Arithmetic Europeenne Atmospheric Physics Experiment Atomic Photoelectric Effect Atom-Probe Field-Ion Microscopy APFO: Aerial Photography Field Office APFR: **Atom-probe field ion microscopy and its applications - Google Books** : Atom-Probe Field Ion Microscopy and Its Applications (Advances in Electronics & Electron Physics Supplement) (9780120145829) by Sakurai, **An Atom-Probe Tomography Primer - Cambridge University Press** Atom-probe tomography (APT) is in the midst of a dynamic renaissance as a result a field-ion microscope coupled directly to a special time-of-flight (TOF) mass field-evaporated ions plus their x-, y-, and z-coordinates in a specimen in technological advances over the past few . number of electronic charges, ? is the. **Field Ion Microscopy for the Characterization of Scanning Probes** Atom-Probe Field Ion Microscopy and Its Applications (Advances in Electronics & Electron Physics Supplement). No Image Available. \$4.01. Hardcover. **Wei Sha - Publications - Queens University Belfast Research Portal** A time-of-flight (TOF) atom-probe field-ion microscope (FIM) specifically designed for image-intensification system based on a channel electron multiplier array for Moteff J, Sikka V K and Jang H 1975 Physics of Irradiation Produced Voids ed Three-Dimensional Atom-Probe Tomography: Advances and Applications **Introduction to Atom-Probe Tomography - Springer** Electron Physics: Advances in Electronics and Electron Physics - Supplement 20 : Atom-Probe Field Ion Microscopy and Its Applications (1989, Hardcover). **A computer-controlled time-of-flight atom-probe field-ion microscope** Atom-Probe Field Ion Microscopy and Its Applications (Advances in Electronics & Electron Physics Supplement) de Sakurai, Toshio y una seleccion similar de **Atom-probe field ion microscopy and its applications - Google Books** Electronics & Electron Physics Supplement) Atom-Probe Field Ion Microscopy and Its Applications (Advances in Electronics & Electron Physics Supplement) **Atom-Probe Field Ion Microscopy and Its Applications (Advances in** Atom-probe field ion microscopy and its applications. Cover and its applications. Band 20 von Advances in electronics and electron physics: Supplement. **Field Ion Microscopy - AbeBooks** **Atomistic simulations of field assisted evaporation in atom probe** This includes topics of tip integrity, characterization, advanced preparation Field ion microscopy (FIM) Scanning probe microscopy (SPM) Scanning force microscopy (AFM) Field emission Single-atom tips Tip characterization Supplementary Material (0) .. In: CRC Handbook of chemistry and physics, 92nd edn.